

Search Notes

Application/Control No.

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Examiner

Shih-wen Hsieh

Applicant(s)/Patent under
Reexamination

YAMADA ET AL.

Art Unit

2861

SEARCHED

Class	Subclass	Date	Examiner
347	22-35	11/10/2005	SWH
358	296	11/10/2005	SWH

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR